

Search Notes

Application/Control No.

10/526,341

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2612

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
340	573.2	7/5/2007	JL
	286.01		
43	539.26		
43/58, 132.1		↓	↓

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	12/22/2006	JL
EAST	7/5/2007	JL
PLUS	7/5/2007	JL